

Search Notes

Application/Control No.

10/032,036

Examiner

James K. Trujillo

Applicant(s)/Patent under
Reexamination

LIN ET AL.

Art Unit

2116

SEARCHED

Class	Subclass	Date	Examiner
713	300,320, 322,323, 324	3/21/2005	JKT
345	173	3/21/2005	JKT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Databases Searched: East NPL: IEEE, ACM see attached.	3/21/2005	JKT